

10/768179

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	(scribe adj line adj monitor) and (stress adj relief adj element) and (main adj die) and area	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/10 11:59
L2	0	(scribe adj line adj monitor) and (stress adj relief adj element) and (main adj die) and area	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/10 11:59
L3	0	(scribe adj line adj monitor) and (stress adj relief adj element) and area	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/10 11:59
L4	0	(scribe adj line adj monitor adj area) and (stress adj relief adj element)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/10 12:01
L5	0	(scribe adj line adj monitor adj area)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/10 12:00
L6	1	("6653710").PN.	USPAT	OR	OFF	2005/08/10 12:01
L7	1	6 and (scribe or monitor or line or surrounding or main or die or stress or relief or element or elements or area or crack or stop)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/10 12:10
L8	3	2002/0086462	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/10 12:08
L9	0	(semiconductor adj arrangement) and (crack adj stop) and (surrounding adj area)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/10 12:10

L10	2	(semiconductor adj arrangement) and (crack adj stop)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/10 12:10
L11	2	10 and (scribe or monitor or line or surrounding or main or die or stress or relief or element or elements or area or crack or stop)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/10 12:10